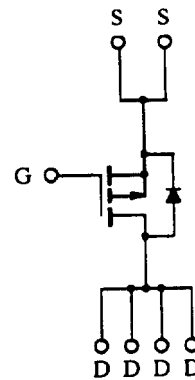
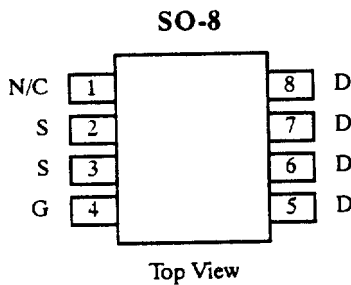


P-Channel Enhancement-Mode MOSFET

Product Summary

| V_{DS} (V) | $r_{DS(on)}$ (Ω) | I_D (A) |
|-----------------|------------------------------|--------------|
| -20 | 0.10 @ $V_{GS} = -10$ V | ± 4.3 |
| | 0.16 @ $V_{GS} = -4.5$ V | ± 3.4 |



P-Channel MOSFET

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

| Parameter | Symbol | Limit | Unit |
|--|----------------|--------------------------|------------------|
| Drain-Source Voltage | V_{DS} | -20 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | |
| Continuous Drain Current ($T_J = 150^\circ\text{C}$) | I_D | $T_A = 25^\circ\text{C}$ | ± 4.3 |
| | | $T_A = 70^\circ\text{C}$ | ± 3.3 |
| Pulsed Drain Current | I_{DM} | ± 20 | A |
| Continuous Source Current (Diode Conduction) | I_S | -2.2 | |
| Maximum Power Dissipation (Surface Mounted on FR4 Board) | P_D | $T_A = 25^\circ\text{C}$ | 2.5 |
| | | $T_A = 70^\circ\text{C}$ | 1.6 |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | -55 to 150 | $^\circ\text{C}$ |

Thermal Resistance Ratings

| Parameter | Symbol | Limit | Unit |
|--|------------|-------|--------------------|
| Maximum Junction-to-Ambient (Surface Mounted on FR4 Board) | R_{thJA} | 50 | $^\circ\text{C/W}$ |

Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

| Parameter | Symbol | Test Condition | Min | Typ ^a | Max | Unit |
|---|--------------|--|---|------------------|-----------|---------------|
| Static | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$ | -0.5 | | | V |
| Gate-Body Leakage | I_{GSS} | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$ | | | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$ | | | -2 | μA |
| | | $V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$ | | | -25 | |
| On-State Drain Current ^b | $I_{D(on)}$ | $V_{DS} \leq -5 \text{ V}, V_{GS} = -10 \text{ V}$ | -20 | | | A |
| | | $V_{DS} \leq -5 \text{ V}, V_{GS} = -4.5 \text{ V}$ | -5 | | | |
| Drain-Source On-State Resistance ^b | $r_{DS(on)}$ | $V_{GS} = -10 \text{ V}, I_D = 2.0 \text{ A}$ | | 0.07 | 0.10 | Ω |
| | | $V_{GS} = -4.5 \text{ V}, I_D = 2.0 \text{ A}$ | | 0.11 | 0.16 | |
| Forward Transconductance ^b | g_{fs} | $V_{DS} = -15 \text{ V}, I_D = -4.3 \text{ A}$ | | 6 | | S |
| Diode Forward Voltage ^b | V_{SD} | $I_S = -1.25 \text{ A}, V_{GS} = 0 \text{ V}$ | | -1.0 | -1.6 | V |
| Dynamic^a | | | | | | |
| Total Gate Charge | Q_g | $V_{DS} = -10 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -4.3 \text{ A}$ | | 29 | 40 | nC |
| Gate-Source Charge | Q_{gs} | | 2.7 | 5 | | |
| Gate-Drain Charge | Q_{gd} | | 14 | 25 | | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = -10 \text{ V}, R_L = 10 \Omega$ $I_D \cong -1 \text{ A}, V_{GEN} = -10 \text{ V}, R_G = 6 \Omega$ | | 15 | 30 | ns |
| Rise Time | t_r | | 30 | 80 | | |
| Turn-Off Delay Time | $t_{d(off)}$ | | 142 | 200 | | |
| Fall Time | t_f | | 130 | 200 | | |
| Source-Drain Reverse Recovery Time | t_{rr} | | $I_F = 1.25 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$ | | 70 | |

Notes:

- a. Guaranteed by design, not subject to production testing.
 b. Pulse test, pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

Typical Characteristics (25°C Unless Otherwise Noted)

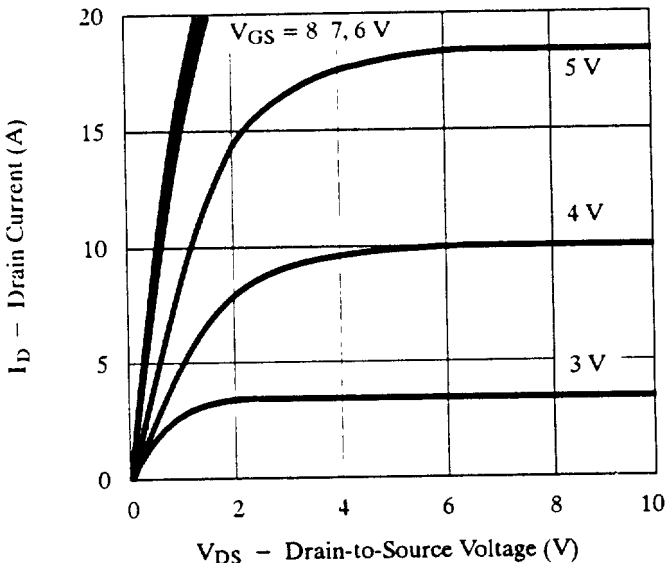


Figure 1: Output Characteristics

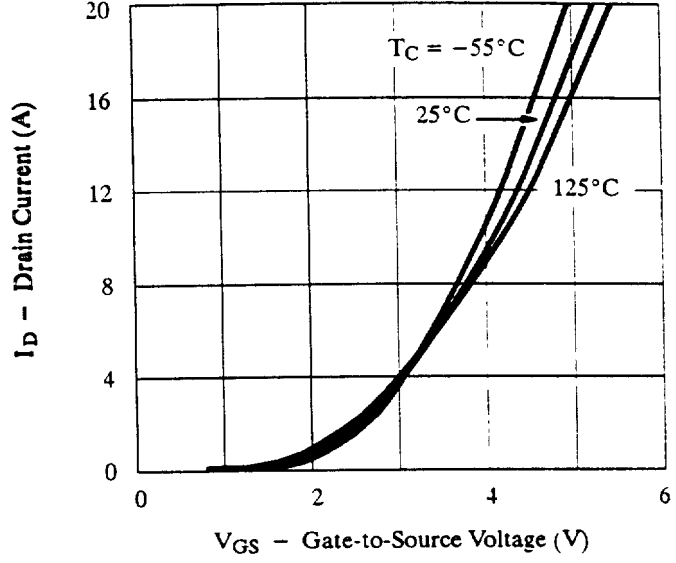


Figure 2: Transfer Characteristics

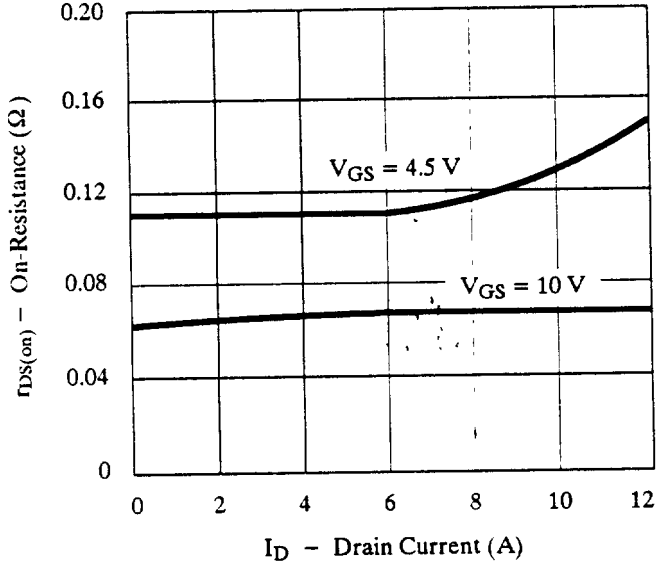


Figure 3: On-Resistance vs. Drain Current

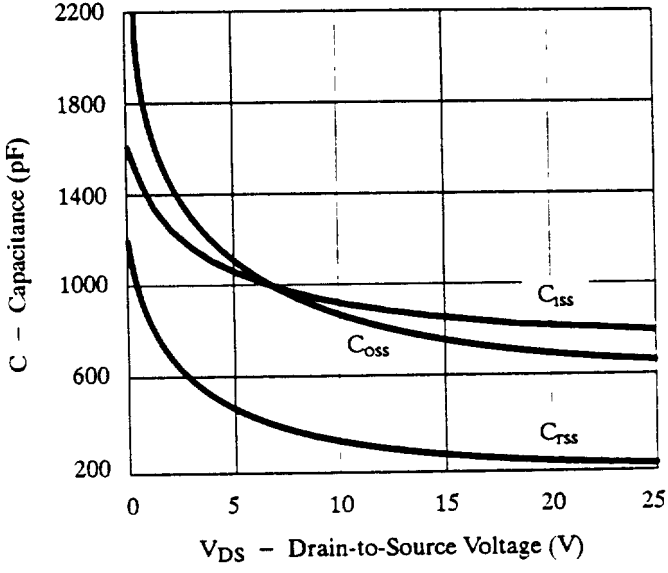


Figure 4: Capacitance

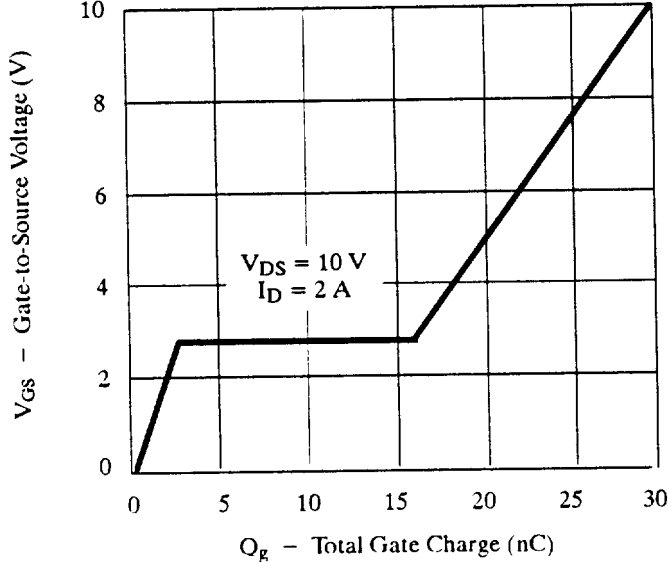


Figure 5: Gate Charge

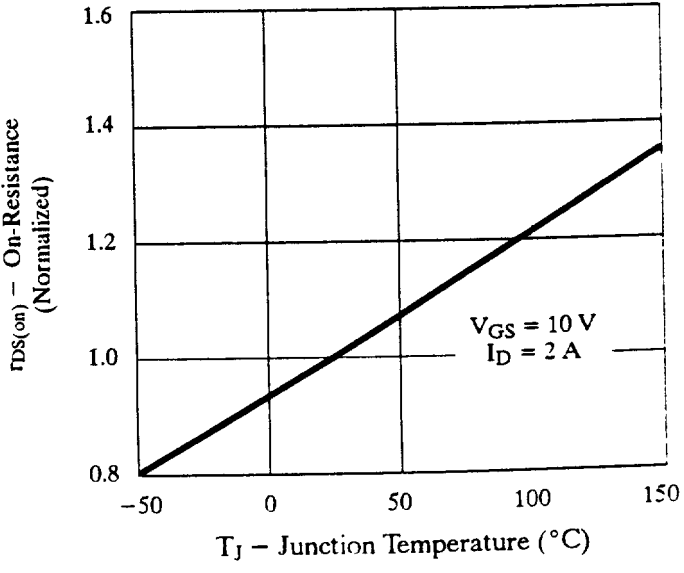


Figure 6: On-Resistance vs. Junction Temperature

Typical Characteristics (25°C Unless Otherwise Noted)

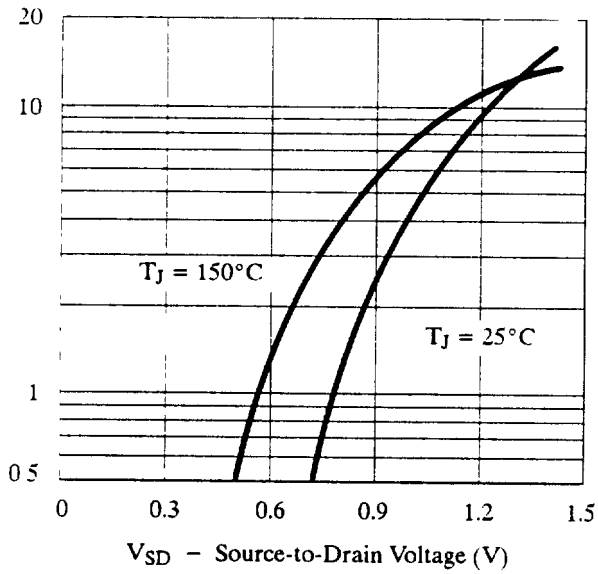


Figure 7: Source-Drain Diode Forward Voltage

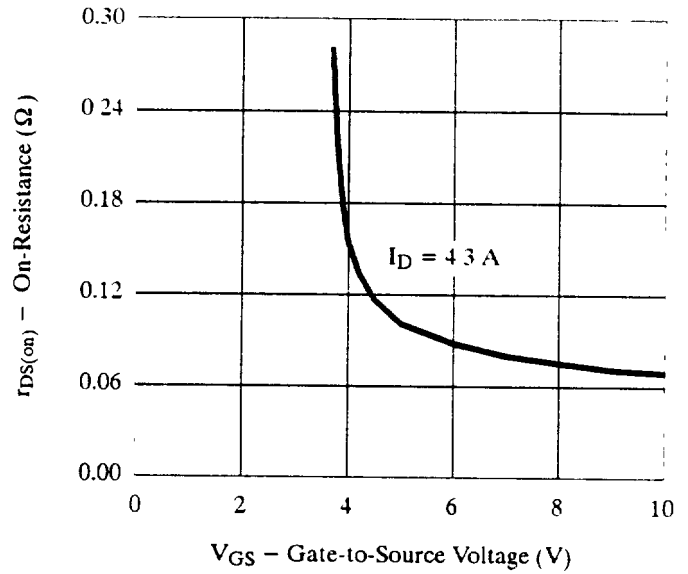


Figure 8: On-Resistance vs. Gate-to-Source Voltage

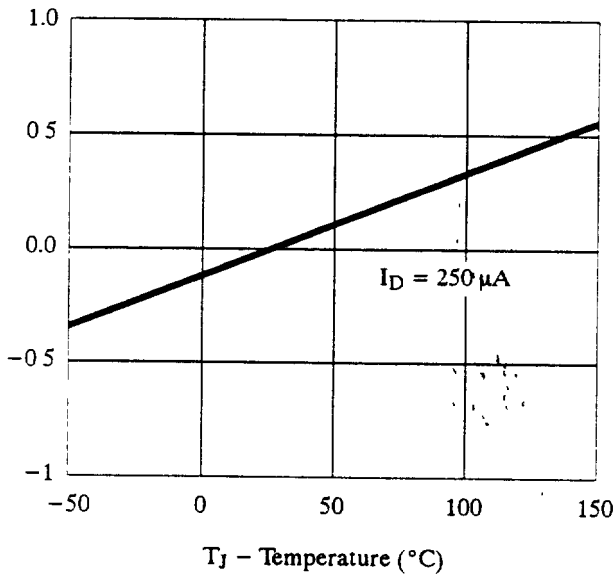


Figure 9: Threshold Voltage

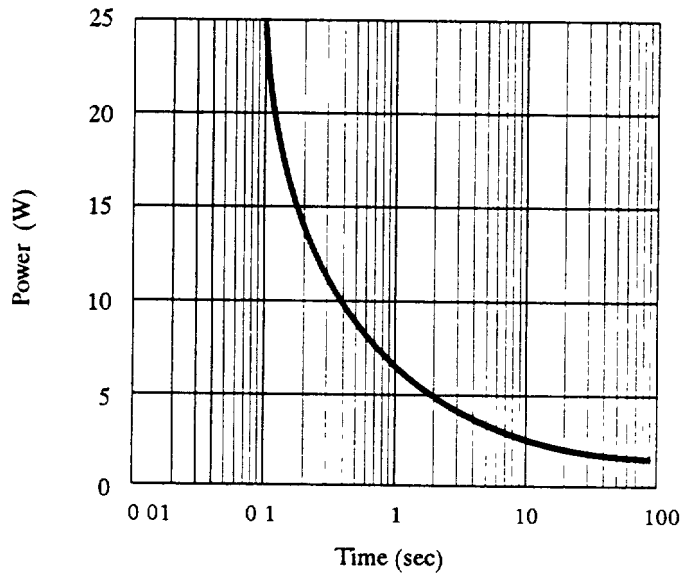


Figure 10: Single Pulse Power

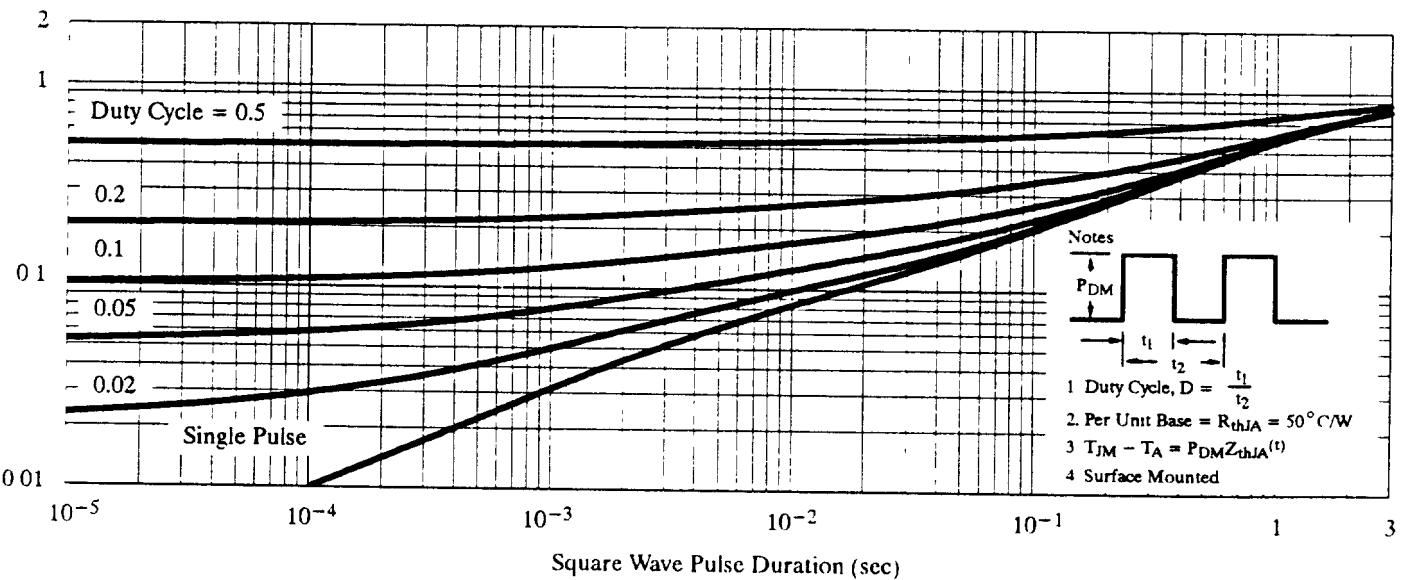


Figure 11: Normalized Effective Transient Thermal Impedance, Junction-to-Ambient